

**IN THE CLAIMS:**

**Please amend** claims 1, 4, 7, and 10 as shown in the complete list of claims that is presented below.

1. (currently amended) A semiconductor integrated circuit comprising:  
m scan chains (wherein m is an integer greater than 1) each of which includes a plurality of logic circuits and a plurality of scan registers connected alternately in series, the scan registers being operated in response to a clock signal, each of the scan chains including a first logic circuit having a data input terminal, a first scan register connected to the first logic circuit, the first scan register having a test input terminal, and a last scan register having an output terminal;

a serial/parallel conversion circuit connected to the test input terminals of the first scan registers of the scan chains, the serial/parallel conversion circuit converting serial data into parallel data in response to a multiplied clock signal having a frequency that is m times of that of the clock signal; and

a parallel/serial conversion circuit connected to the output terminals of the last scan registers of the scan chains, the parallel/serial conversion circuit converting parallel data received from the scan chains into serial data in response to the multiplied clock signal. signal,

wherein the parallel/serial conversion circuit comprises a selector that receives the clock signal and selectively outputs data from the last scan registers of the scan chains in response to the clock signal, and a flip-flop that receives the multiplied clock signal and latches output data from the selector in response to the multiplied clock signal.

2. (previously presented) A semiconductor integrated circuit according to claim 1, further comprising a multiplication circuit connected to the serial/parallel conversion circuit and the parallel/serial conversion circuit, the multiplication circuit receiving the clock signal and generating the multiplied clock signal based on the clock signal.

3. (previously presented) A semiconductor integrated circuit according to claim 1, wherein the serial/parallel conversion circuit includes a plurality of flip-flops

connected in series, the flip-flops being operated in response to the multiplied clock signal.

4. (currently amended) A semiconductor integrated circuit according to claim 1, wherein the parallel/serial conversion circuit ~~including a plurality of flip-flops and a selector, the flip-flops being operated in response to the multiplied clock signal, further includes at least one additional flop-flop that receives the multiplied clock signal.~~

5. (previously presented) A semiconductor integrated circuit according to claim 1, wherein each of the scan registers includes a selector and a flip-flop operated in response to the clock signal.

6. (previously presented) A semiconductor integrated circuit according to claim 1, wherein the output terminal of the last scan register of one of the scan chains is connected to the data input terminal of the first logic circuit of another one of the scan chains.

7. (currently amended) A semiconductor integrated circuit comprising:  
a plurality of scan chains each of which includes a first logic circuit having a data input terminal, a first scan register connected to the first logic circuit, the first scan register having a test input terminal, and a last scan register having an output terminal, the scan registers being operated in response to a clock signal;

a serial/parallel conversion circuit connected to the test input terminals of the first scan registers of the scan chains, the serial/parallel conversion circuit converting serial data into parallel data in response to a multiplied clock signal having a frequency that is substantially equal to the number of scan chains times the frequency of the clock signal; and

a parallel/serial conversion circuit connected to the output terminals of the last scan registers of the scan chains, the parallel/serial conversion circuit converting parallel

data received from the scan chains into serial data in response to the multiplied clock signal. signal,

wherein the parallel/serial conversion circuit comprises a selector that receives the clock signal and selectively outputs data from the last scan registers of the scan chains in response to the clock signal, and a flip-flop that receives the multiplied clock signal and latches output data from the selector in response to the multiplied clock signal.

8. (previously presented) A semiconductor integrated circuit according to claim 7, further comprising a multiplication circuit connected to the serial/parallel conversion circuit and the parallel/serial conversion circuit, the multiplication circuit receiving the clock signal and generating the multiplied clock signal based on the clock signal.

9. (previously presented) A semiconductor integrated circuit according to claim 7, wherein the serial/parallel conversion circuit includes a plurality of flip-flops connected in series, the flip-flops being operated in response to the multiplied clock signal.

10. (currently amended) A semiconductor integrated circuit according to claim 7, wherein the parallel/serial conversion circuit further includes a plurality of flip-flops and a selector, the flip-flops being operated in response to at least one additional flip-flop that receives the multiplied clock signal.

11. (previously presented) A semiconductor integrated circuit according to claim 7, wherein each of the scan registers includes a selector and a flip-flop operated in response to the clock signal.

12. (previously presented) A semiconductor integrated circuit according to claim 7, wherein the selectors of the scan registers are operated in response to a mode signal.

Claim 13-14 (cancelled).